Search Notes (continued)

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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/775,080	SAKIYAMA ET AL.	
Examiner	Art Unit	
Chun-Kuan (Mike) Lee	2181	

	SEAR	CHED	
Class	Subclass	Date	Examiner
710	2	3/8/2006	CHW- KUAN Lee
710	13	3/8/2006	
710	17	3/8/2006	
710	68	3/8/2006	
710	74	3/8/2006	
710	300-301	3/8/2006	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		')
	DATE	EXMR
(EAST) US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	3/8/2006	CHAN- KUAN Lee
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